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MAY 2015

FQB1P50

P-Channel QFET® MOSFET

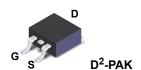
- 500 V, - 1.5 A, 10.5 Ω

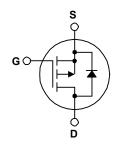
Description

This P-Channel enhancement mode power MOSFET is produced using Fairchild Semiconductor's proprietary planar stripe and DMOS technology. This advanced MOSFET technology has been especially tailored to reduce on-state resistance, and to provide superior switching performance and high avalanche energy strength. These devices are suitable for switched mode power supplies, active power factor correction (PFC), and electronic lamp ballasts.

Features

- - 1.5 A, 500 V, $R_{DS(on)}$ = 10.5 Ω (Max.) @ V_{GS} = 10 V, I_{D} = 0.75 A
- Low Gate Charge (Typ. 11 nC)
- Low Crss (Typ. 6.0 pF)
- 100% Avalanche Tested
- RoHS Compliant





Absolute Maximum Ratings $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter		FQB1P50TM	Unit
V_{DSS}	Drain-Source Voltage		-500	V
I _D	Drain Current - Continuous (T _C = 25°C)		-1.5	А
	- Continuous (T _C = 100°C))	-0.95	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	-6.0	Α
V _{GSS}	Gate-Source Voltage		± 30	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	110	mJ
I _{AR}	Avalanche Current	(Note 1)	-1.5	Α
E _{AR}	Repetitive Avalanche Energy	(Note 1)	6.3	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	-4.5	V/ns
P _D	Power Dissipation (T _A = 25°C) *		3.13	W
	Power Dissipation (T _C = 25°C)		63	W
	- Derate above 25°C		0.51	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C
T _L	Maximum lead temperature for soldering, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	FQB1P50TM	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max	1.98	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (minimum pad of 2 oz copper), Max.	62.5	°C/W
	Thermal Resistance, Junction to Ambient (1 in ² pad of 2 oz copper), Max.	40	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FQB1P50	FQB1P50TM	D2-PAK	330mm	24mm	800

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FI	arica	l Chara	actai	ristics
_	C 1 L a	. Vilai	166	เมอเเนอ

T_C = 25°C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Off Cha	aracteristics					
BV_DSS	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = -250 \mu\text{A}$	-500	1		٧
ΔBV_{DSS} / ΔT_{J}	Breakdown Voltage Temperature Coefficient	I_D = -250 μA, Referenced to 25°C		-		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = -500 V, V _{GS} = 0 V V _{DS} = -400 V, T _C = 125°C			-1 -10	μA μA
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = -30 V, V _{DS} = 0 V		1	-100	nA
I_{GSSR}	Gate-Body Leakage Current, Reverse	$V_{GS} = 30 \text{ V}, V_{DS} = 0 \text{ V}$			100	nA

On Characteristics

$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = -250 \mu\text{A}$	-3.0		-5.0	V
R _{DS(on)}	Static Drain-Source On-Resistance	V _{GS} = -10 V, I _D = -0.75 A		8.0	10.5	Ω
9 _{FS}	Forward Transconductance	$V_{DS} = -50 \text{ V}, I_{D} = -0.75 \text{ A}$		1.26		S

Dynamic Characteristics

C_{iss}	Input Capacitance	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V},$	 270	350	pF
C _{oss}	Output Capacitance	f = 1.0 MHz	 40	50	pF
C_{rss}	Reverse Transfer Capacitance		 6.0	8.0	pF

Switching Characteristics

t _{d(on)}	Turn-On Delay Time	V _{DD} = -250 V, I _D = -1.5 A,	 9.0	30	ns
t _r	Turn-On Rise Time	$R_{G} = 25 \Omega$	 25	60	ns
t _{d(off)}	Turn-Off Delay Time	1.6 - 20 32	 27	65	ns
t _f	Turn-Off Fall Time	(Note 4)	 30	70	ns
Q_g	Total Gate Charge	$V_{DS} = -400 \text{ V}, I_{D} = -1.5 \text{ A},$	 11	14	nC
Q_{gs}	Gate-Source Charge	V _{GS} = -10 V	 2.0		nC
Q_{gd}	Gate-Drain Charge	(Note 4)	 5.6		nC

Drain-Source Diode Characteristics and Maximum Ratings

Diam-Source Diode Characteristics and Maximum Natings							
IS	Maximum Continuous Drain-Source Diode Forward Current				-1.5	Α	
I _{SM}	Maximum Pulsed Drain-Source Diode Forward Current				-6.0	Α	
V_{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_{S} = -1.5 \text{ A}$			-5.0	V	
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_{S} = -1.5 \text{ A,}$		200		ns	
Q_{rr}	Reverse Recovery Charge	$dI_{F} / dt = 100 A/\mu s$		0.7		μС	

- 1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 88mH, I_{AS} = -1.5A, V_{DD} = -50V, R_G = 25 Ω , Starting T_J = 25°C 3. I_{SD} ≤ -1.5A, di/dt ≤ 200A/ μ s, V_{DD} ≤ BV $_{DSS}$, Starting T_J = 25°C

- 4. Essentially independent of operating temperature

Typical Characteristics

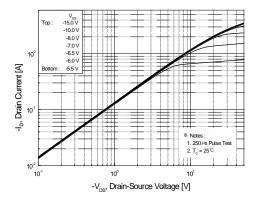


Figure 1. On-Region Characteristics

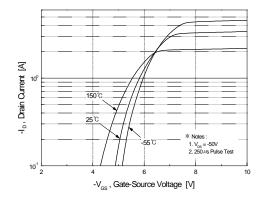


Figure 2. Transfer Characteristics

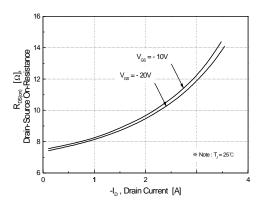


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

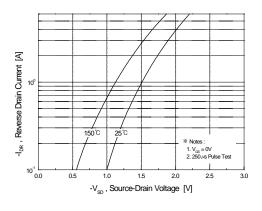


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

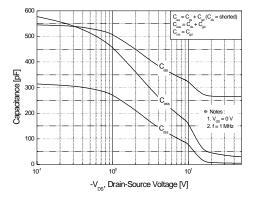


Figure 5. Capacitance Characteristics

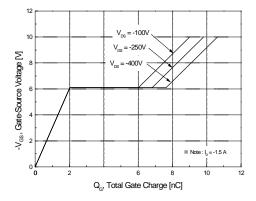


Figure 6. Gate Charge Characteristics

Typical Characteristics (Continued)

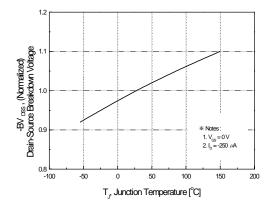
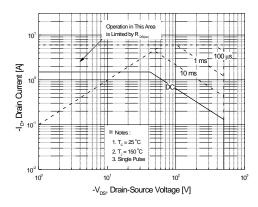


Figure 7. Breakdown Voltage Variation vs. Temperature

Figure 8. On-Resistance Variation vs. Temperature



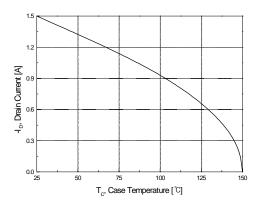


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs. Case Temperature

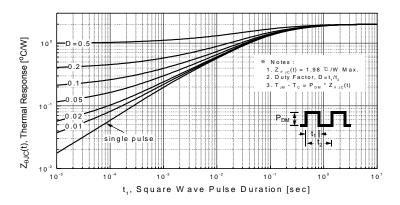


Figure 11. Transient Thermal Response Curve



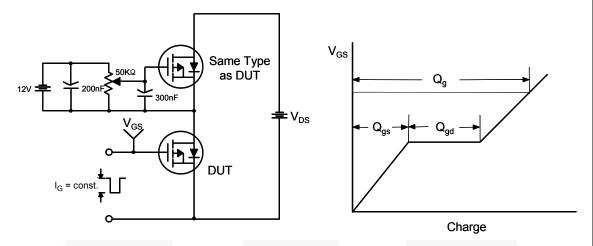


Figure 13. Resistive Switching Test Circuit & Waveforms

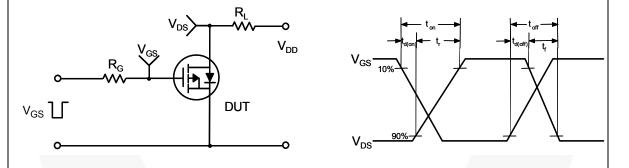
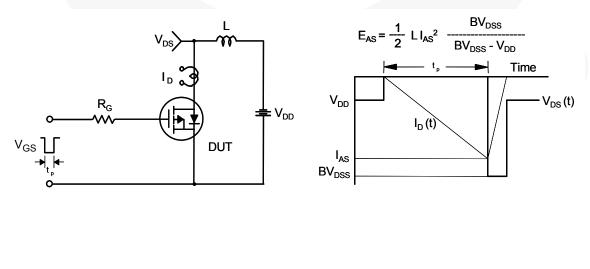
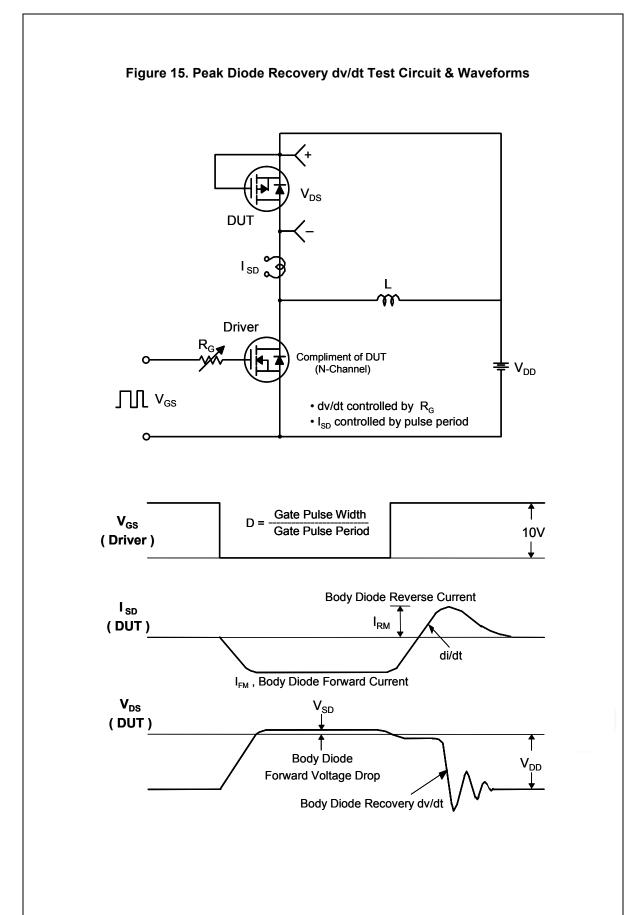
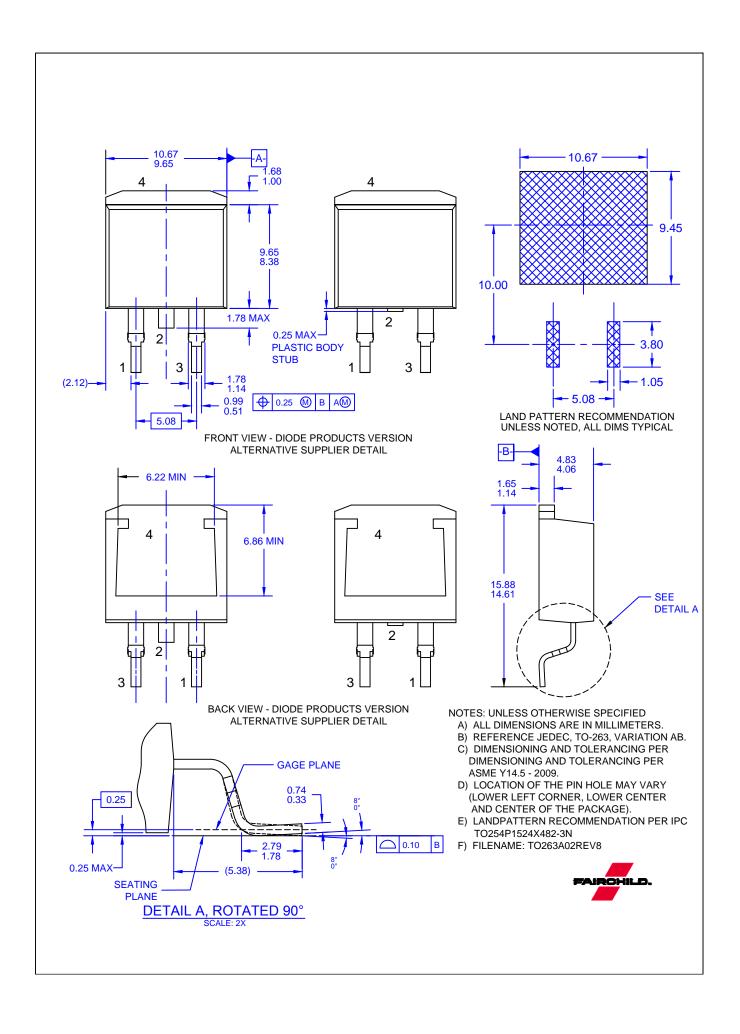


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms







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